



✓ 2829 #

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE
(Case No. 219.003-US)

In the Application of: **Yamada**

Serial No: **09/865,528**

Filed: **May 29, 2001**

Title: **Semiconductor Device Test Method and
Semiconductor Device Tester**

)
) Group
) Art Unit: **2829**
)
) Before
) Examiner: **V. Nguyen**
)
)

Commissioner for Patents
P. O. Box 1450
Alexandria, VA 22313-1450

FEE TRANSMITTAL

Dear Sir:

Transmitted herewith is an **Information Disclosure Statement** (1 page + Form PTO-1449 (1 sheet) and references cited therein.

The fee has been calculated as shown below:

CLAIMS AS AMENDED						
	Claims Remaining	Highest Number Previously Paid	Extra	Rate		Amount
				Large	Small	
Number of Claims In (in excess of 20)	0	0	0	\$18.00	\$9.00	-0-
Independent Claims (in excess of 3)	0	0	0	\$84.00	\$42.00	-0-
Extension Fee: a) One Month				\$110.00	\$55.00	-0-
Filing of Information Disclosure Statement (37 C.F.R. §1.17(p)):						\$180.00
TOTAL FEE DUE:						\$180.00

Method of Payment:

[XX] A check payable to the Commissioner of Patents and Trademarks, in the amount of \$180.00 is enclosed as payment of the Total Fee.

[] Please charge my Deposit Acc. 50-0763 in the amount of \$_____ to cover the above fees. A duplicate copy of this sheet is enclosed.

[XX] The Commissioner is hereby authorized to charge any fees that may be required, or credit any overpayment to Deposit Acc. 50-0763. A duplicate copy of this sheet is enclosed.

Date: May 5, 2004

Respectfully submitted,

Neil Steinberg, Reg. No. 34,735
Telephone No. (650) 968-8079



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE
(219.001-US)

In re Application of: **YAMADA**

Serial No: **09/451,440**

Filed: **NOVEMBER 30, 1999**

Title: **CONTACT HOLE STANDARD TEST DEVICE**

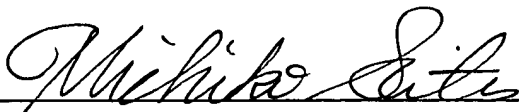
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Certificate of Mailing under 37 CFR 1.8

I hereby certify that the attached: **(1)** Information Disclosure Statement (1 page + Modified PTO-1449 (1 sheet) and References cited therein); **(2)** Fee Transmittal (1 page + 1 copy thereof); **(3)** Check (\$180.00) are being deposited with the United States Postal Service with sufficient postage as first class mail in an envelope addressed to:

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

on May 5, 2004.



Signature



Print Name of Person Signing Certificate



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Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

INFORMATION DISCLOSURE STATEMENT

Dear Sir:

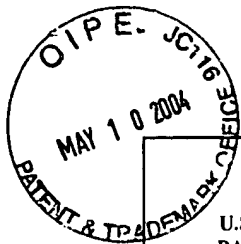
Submitted herewith is one (1) sheet of a modified Form PTO-1449. A copy of each document cited on the attached Form PTO-1449 is also submitted.

It is respectfully requested that the Examiner make his/her consideration of these documents formally of record with the initial Office Action.

Respectfully submitted,

Date: May 5, 2004

Neil A. Steinberg
Reg. No. 34,735
650-968-8079



PTO-1449 (Modified) U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE INFORMATION DISCLOSURE STATEMENT BY APPLICANT	ATTY. DOCKET NO. 219.003-US	SERIAL NUMBER 09/865,528
	APPLICANT(S) Yamada	
	FILING DATE May 29, 2001	GROUP ART UNIT 2829

U.S. PATENT DOCUMENTS

EXAMINER INITIALS	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE
	5,989,919					

FOREIGN PATENT DOCUMENTS

EXAMINER INITIALS	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB CLASS	TRANSLATION YES/NO	
	63-009807	1/1988	Japan				

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

	"An In-Line Contact and Via Hole Inspection Method Using Electron Beam Compensation Current", Yamada et al., IEEE 1999, Doc. No. 0-7803-5413-3/99/, available from http://www.fabsol.com/us/images/library/21.pdf

EXAMINER	DATE CONSIDERED
EXAMINER: Initial citation if reference was considered. Draw line through citation if not in conformance to MPEP 609 and not considered. Include copy of this form with next communication to applicant.	